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 $4 \text{ M SRAM} (512\text{-kword} \times 8\text{-bit})$



ADE-203-903D (Z) Rev. 3.0 Aug. 24, 1999

Description

The Hitachi HM628512B is a 4-Mbit static RAM organized 512-kword \times 8-bit. It realizes higher density, higher performance and low power consumption by employing 0.35 μ m Hi-CMOS process technology. The device, packaged in a 525-mil SOP (foot print pitch width) or 400-mil TSOP TYPE II or 600-mil plastic DIP, is available for high density mounting. The HM628512B is suitable for battery backup system.

Features

Single 5 V supply

• Access time: 55/70 ns (max)

Power dissipation

Active: 50 mW/MHz (typ)Standby: 10 µW (typ)

Completely static memory. No clock or timing strobe required

Equal access and cycle times

• Common data input and output: Three state output

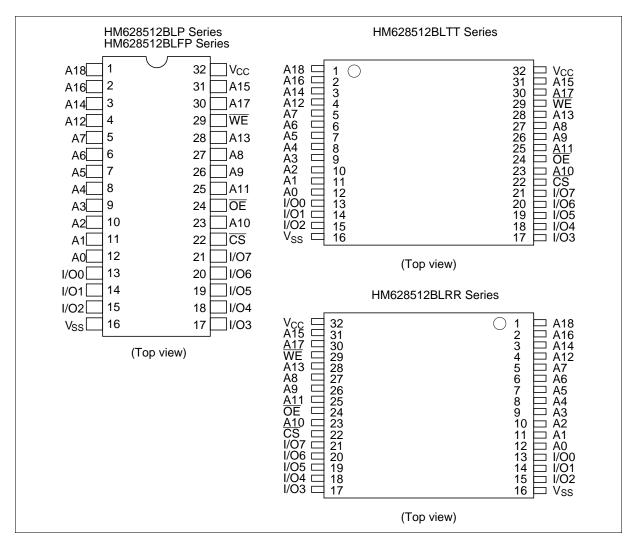
• Directly TTL compatible: All inputs and outputs

Battery backup operation

Ordering Information

Type No.	Access time	Package
HM628512BLP-5 HM628512BLP-7	55 ns 70 ns	600-mil 32-pin plastic DIP (DP-32)
HM628512BLP-5SL HM628512BLP-7SL	55 ns 70 ns	_
HM628512BLP-5UL HM628512BLP-7UL	55 ns 70 ns	_
HM628512BLFP-5 HM628512BLFP-7	55 ns 70 ns	525-mil 32-pin plastic SOP (FP-32D)
HM628512BLFP-5SL HM628512BLFP-7SL	55 ns 70 ns	_
HM628512BLFP-5UL HM628512BLFP-7UL	55 ns 70 ns	_
HM628512BLTT-5 HM628512BLTT-7	55 ns 70 ns	400-mil 32-pin plastic TSOP II (TTP-32D)
HM628512BLTT-5SL HM628512BLTT-7SL	55 ns 70 ns	_
HM628512BLTT-5UL HM628512BLTT-7UL	55 ns 70 ns	_
HM628512BLRR-5 HM628512BLRR-7	55 ns 70 ns	400-mil 32-pin plastic TSOP II reverse (TTP-32DR)
HM628512BLRR-5SL HM628512BLRR-7SL	55 ns 70 ns	_
HM628512BLRR-5UL HM628512BLRR-7UL	55 ns 70 ns	

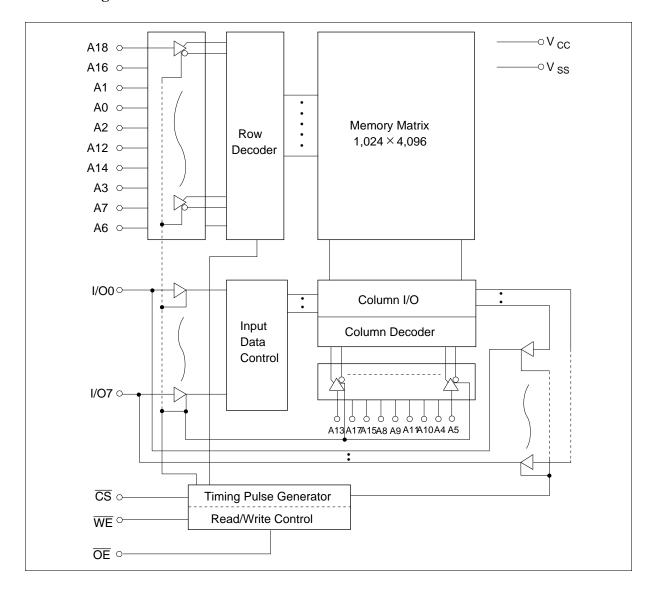
Pin Arrangement



Pin Description

Pin name	Function			
A0 to A18	Address input			
I/O0 to I/O7	Data input/output			
CS	Chip select			
ŌĒ	Output enable			
WE	Write enable			
V _{cc}	Power supply			
V _{ss}	Ground			

Block Diagram



Function Table

WE	CS	OE	Mode	V _{cc} current	Dout pin	Ref. cycle
×	Н	×	Not selected	I_{SB}, I_{SB1}	High-Z	_
Н	L	Н	Output disable	I _{cc}	High-Z	_
Н	L	L	Read	I _{cc}	Dout	Read cycle
L	L	Н	Write	I _{cc}	Din	Write cycle (1)
L	L	L	Write	I _{cc}	Din	Write cycle (2)

Note: x: H or L

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Power supply voltage	V _{cc}	-0.5 to +7.0	V
Voltage on any pin relative to V _{ss}	V _T	-0.5^{*1} to $V_{CC} + 0.3^{*2}$	V
Power dissipation	P _T	1.0	W
Operating temperature	Topr	-20 to +70	°C
Storage temperature	Tstg	-55 to +125	°C
Storage temperature under bias	Tbias	-20 to +85	°C

Notes: 1. -3.0 V for pulse half-width ≤ 30 ns

2. Maximum voltage is 7.0 V

Recommended DC Operating Conditions ($Ta = -20 \text{ to } +70^{\circ}\text{C}$)

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	V _{cc}	4.5	5.0	5.5	V
	V _{SS}	0	0	0	V
Input high voltage	V_{IH}	2.2	_	V_{cc} + 0.3	V
Input low voltage	V _{IL}	-0.3 ^{*1}	_	0.8	V

Note: 1. -3.0 V for pulse half-width $\leq 30 \text{ ns}$

DC Characteristics (Ta = -20 to +70°C, V_{CC} = 5 V $\pm 10\%$, V_{SS} = 0 V)

Parameter	Symbol	Min	Typ*1	Max	Unit	Test conditions
Input leakage current	I _u	_	_	1	μΑ	$Vin = V_{SS}$ to V_{CC}
Output leakage current	I _{LO}	_	_	1	μΑ	$ \frac{\overline{CS} = V_{IH} \text{ or } \overline{OE} = V_{IH} \text{ or} }{\overline{WE} = V_{IL}, V_{I/O} = V_{SS} \text{ to } V_{CC}} $
Operating power supply current: DC	I _{cc}	_	8	15	mA	$\overline{\text{CS}} = \text{V}_{\text{IL}},$ others = $\text{V}_{\text{IH}}/\text{V}_{\text{IL}}, \text{I}_{\text{I/O}} = 0 \text{ mA}$
Operating power supply current	I _{CC1}	_	40	60	mA	$\label{eq:min_cycle} \begin{split} & \underbrace{\text{Min cycle, duty}}_{\text{ICS}} = V_{\text{IL}}, \text{ others} = V_{\text{IH}}/V_{\text{IL}} \\ & I_{\text{I/O}} = 0 \text{ mA} \end{split}$
Operating power supply current	I _{CC2}	_	10	20	mA	$\begin{split} & \text{Cycle time} = 1 \; \mu\text{s}, \\ & \text{duty} = 100\% \\ & \text{I}_{\text{I/O}} = 0 \; \text{mA}, \; \overline{\text{CS}} \leq 0.2 \; \text{V} \\ & \text{V}_{\text{IH}} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V}, \; \text{V}_{\text{IL}} \leq 0.2 \; \text{V} \end{split}$
Standby power supply current: DC	I _{SB}	_	1	3	mΑ	CS = V _{IH}
Standby power supply current (1): DC	I _{SB1}	_	2*2	100*2	μΑ	$Vin \ge 0 \text{ V}, \overline{CS} \ge V_{CC} - 0.2 \text{ V}$
		_	2* ³	50*3	μΑ	_
		_	2*4	20*4	μΑ	_
Output low voltage	V _{OL}	_	_	0.4	V	I _{OL} = 2.1 mA
Output high voltage	V_{OH}	2.4	_	_	V	I _{OH} = -1.0 mA

Notes: 1. Typical values are at $V_{CC} = 5.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and specified loading, and not guaranteed.

- 2. This characteristics is guaranteed only for L version.
- 3. This characteristics is guaranteed only for L-SL version.
- 4. This characteristics is guaranteed only for L-UL version.

Capacitance (Ta = +25°C, f = 1 MHz)

Parameter	Symbol	Тур	Max	Unit	Test conditions
Input capacitance*1	Cin	_	8	pF	Vin = 0 V
Input/output capacitance*1	C _{I/O}	_	10	pF	V _{I/O} = 0 V

Note: 1. This parameter is sampled and not 100% tested.

AC Characteristics (Ta = -20 to +70 °C, V_{CC} = 5 V \pm 10%, unless otherwise noted.)

Test Conditions

• Input pulse levels: 0.8 V to 2.4 V

• Input rise and fall time: 5 ns

• Input and output timing reference levels: 1.5 V

• Output load: $1 \text{ TTL Gate} + C_L (100 \text{ pF}) (HM628512B-7)$

 $1 \text{ TTL Gate} + C_L (50 \text{ pF}) (HM628512B-5)$

(Including scope & jig)

Read Cycle

		HM628	8512B				
		-5		-7		<u> </u>	
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{RC}	55	_	70	_	ns	
Address access time	t _{AA}	_	55	_	70	ns	
Chip select access time	t _{co}	_	55	_	70	ns	
Output enable to output valid	t _{oe}	_	25	_	35	ns	
Chip selection to output in low-Z	t _{LZ}	10	_	10	_	ns	2
Output enable to output in low-Z	t_{OLZ}	5	_	5	_	ns	2
Chip deselection to output in high-Z	t _{HZ}	0	20	0	25	ns	1, 2
Output disable to output in high-Z	t_{OHZ}	0	20	0	25	ns	1, 2
Output hold from address change	t _{oh}	10	_	10	_	ns	

Output disable to output in high-Z

Write Cycle

		HIVI028312B					
		-5		-7			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t _{wc}	55	_	70	_	ns	
Chip selection to end of write	t _{cw}	50	_	60	_	ns	4
Address setup time	t _{AS}	0	_	0	_	ns	5
Address valid to end of write	t _{AW}	50	_	60	_	ns	
Write pulse width	t _{WP}	40	_	50	_	ns	3, 12
Write recovery time	t _{wR}	0	_	0	_	ns	6
WE to output in high-Z	t _{wHZ}	0	20	0	25	ns	1, 2, 7
Data to write time overlap	$t_{\scriptscriptstyle DW}$	25	_	30	_	ns	
Data hold from write time	t _{DH}	0	_	0	_	ns	
Output active from output in high-Z	t _{ow}	5	_	5	_	ns	2

HM628512B

Notes: 1. t_{HZ} , t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

0

- 2. This parameter is sampled and not 100% tested.
- 3. A write occurs during the overlap (t_{WP}) of a low \(\overline{CS}\) and a low \(\overline{WE}\). A write begins at the later transition of \(\overline{CS}\) going low or \(\overline{WE}\) going low. A write ends at the earlier transition of \(\overline{CS}\) going high or \(\overline{WE}\) going high. t_{WP} is measured from the beginning of write to the end of write.

20

25

ns

1, 2, 7

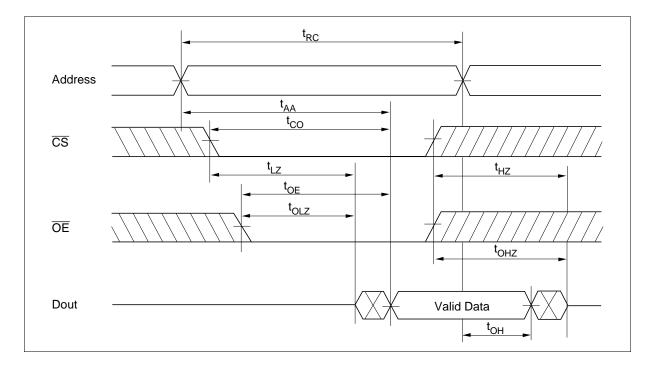
- 4. t_{CW} is measured from \overline{CS} going low to the end of write.
- 5. t_{AS} is measured from the address valid to the beginning of write.

 t_{OHZ}

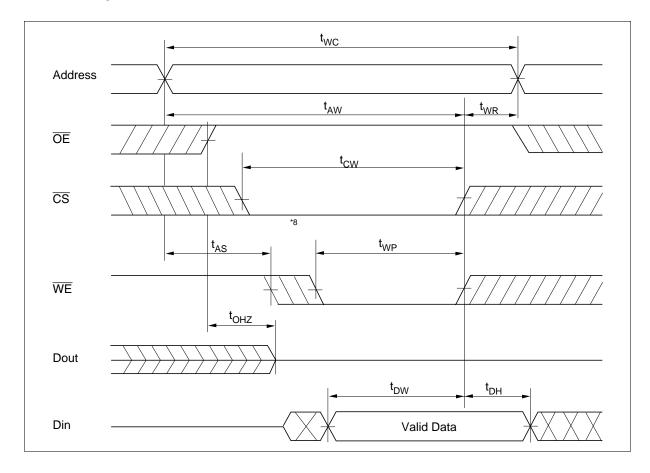
- 6. t_{wR} is measured from the earlier of \overline{WE} or \overline{CS} going high to the end of write cycle.
- 7. During this period, I/O pins are in the output state so that the input signals of the opposite phase to the outputs must not be applied.
- 8. If the $\overline{\text{CS}}$ low transition occurs simultaneously with the $\overline{\text{WE}}$ low transition or after the $\overline{\text{WE}}$ transition, the output remain in a high impedance state.
- 9. Dout is the same phase of the write data of this write cycle.
- 10. Dout is the read data of next address.
- 11. If \overline{CS} is low during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.
- 12. In the write cycle with \overline{OE} low fixed, t_{WP} must satisfy the following equation to avoid a problem of data bus contention. $t_{WP} \ge t_{DW}$ min + t_{WHZ} max

Timing Waveforms

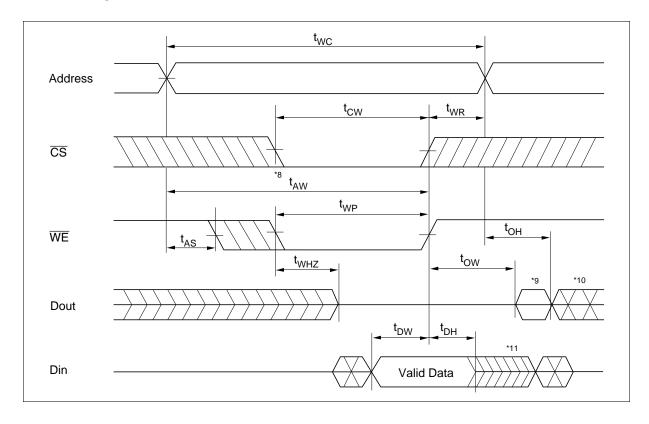
Read Timing Waveform $(\overline{WE}=V_{IH})$



Write Timing Waveform (1) (OE Clock)



Write Timing Waveform (2) $(\overline{OE} Low Fixed)$



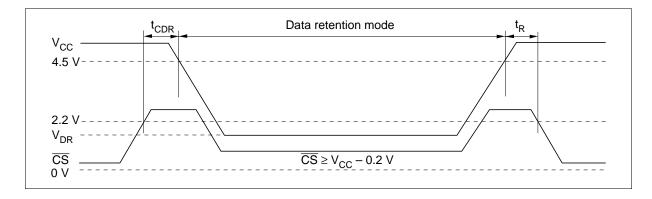
Low V_{CC} **Data Retention Characteristics** ($Ta = -20 \text{ to } +70^{\circ}\text{C}$)

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions*4
V _{cc} for data retention	V_{DR}	2	_	_	V	$\overline{\text{CS}} \ge \text{V}_{\text{CC}} - 0.2 \text{ V, Vin} \ge 0 \text{ V}$
Data retention current	I _{CCDR}	_	1* ⁵	50* ¹	μА	$\frac{V_{CC}}{CS} = 3.0 \text{ V}, \text{ Vin } \ge 0 \text{ V}$ $\overline{CS} \ge V_{CC} - 0.2 \text{ V}$
		_	1*5	15* ²	μΑ	
		_	1* ⁵	10* ³	μΑ	
Chip deselect to data retention time	t _{CDR}	0	_	_	ns	See retention waveform
Operation recovery time	t _R	t _{RC} *6	_	_	ns	

Notes: 1. For L-version and 20 μ A (max.) at Ta = -20 to +40°C.

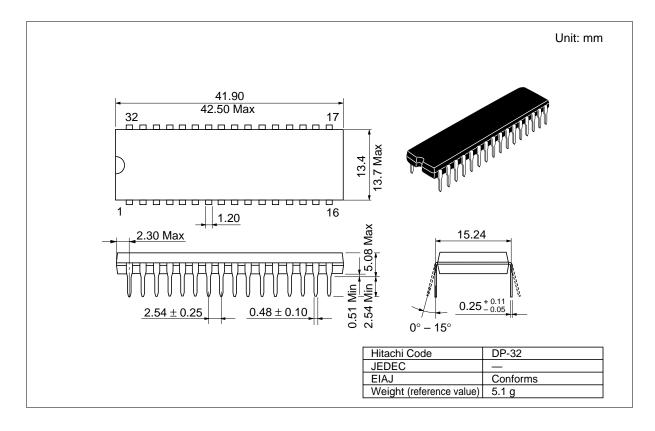
- 2. For L-SL-version and 3 μ A (max.) at Ta = -20 to +40°C.
- 3. For L-UL-version and 3 μ A (max.) at Ta = -20 to +40°C.
- 4. $\overline{\text{CS}}$ controls address buffer, $\overline{\text{WE}}$ buffer, $\overline{\text{OE}}$ buffer, and Din buffer. In data retention mode, Vin levels (address, $\overline{\text{WE}}$, $\overline{\text{OE}}$, I/O) can be in the high impedance state.
- 5. Typical values are at $V_{\rm CC}$ = 3.0 V, Ta = +25°C and specified loading, and not guaranteed.
- 6. t_{RC} = read cycle time.

Low V_{CC} Data Retention Timing Waveform (\overline{CS} Controlled)



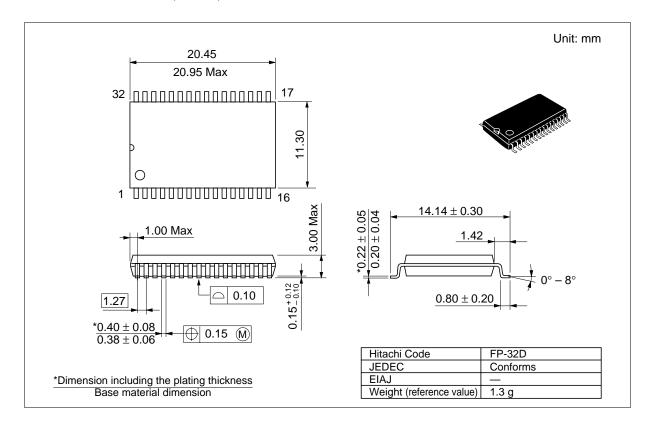
Package Dimensions

HM628512BLP Series (DP-32)



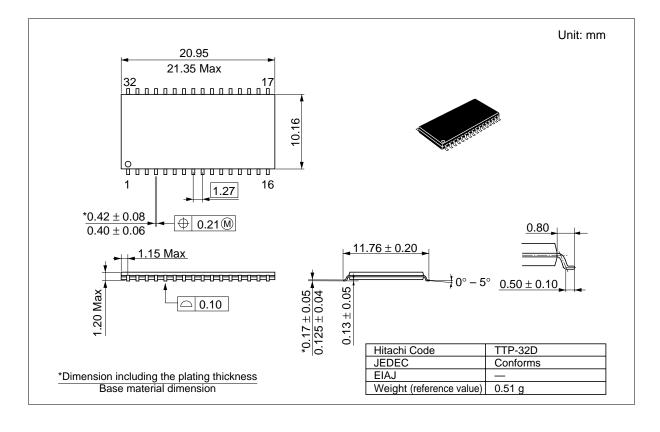
Package Dimensions (cont.)

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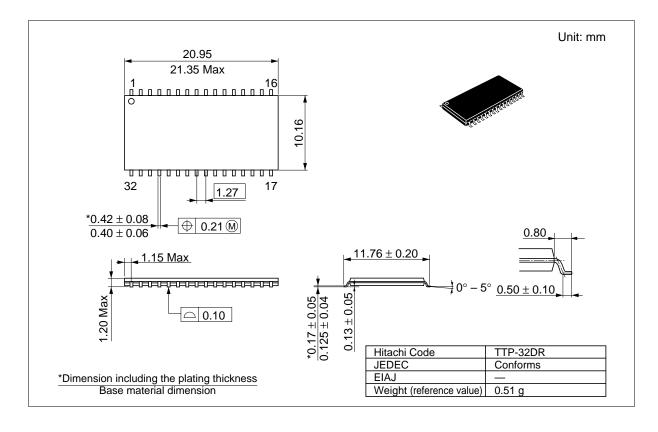
Package Dimensions (cont.)

HM628512BLTT Series (TTP-32D)



Package Dimensions (cont.)

HM628512BLRR Series (TTP-32DR)



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